


<b>Search Notes</b>  	<b>Application/Control No.</b>  09605293	<b>Applicant(s)/Patent Under Reexamination</b>  CHAPEK, DAVID L.
	<b>Examiner</b>  Matthew C Landau	<b>Art Unit</b>  2815

SEARCHED			
Class	Subclass	Date	Examiner
257	E21.212	3/25/2008	MCL

SEARCH NOTES		
Search Notes	Date	Examiner
EAST search (printout included)	3/25/08	MCL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner